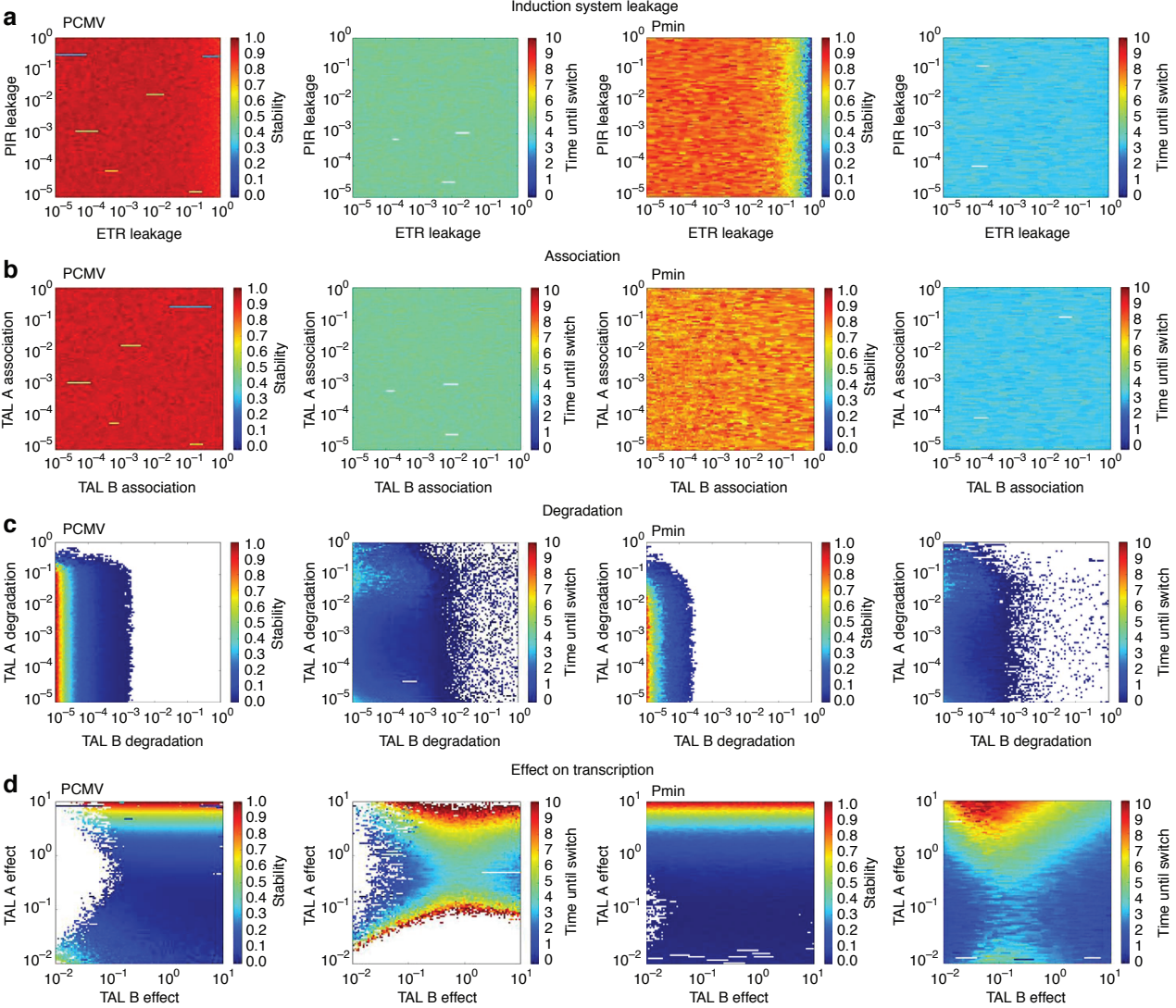
a
Induction system leakage
PCMV
Pmin
PIR leakage
ETR leakage
Stability
Time until switch
b
Association
TAL A association
TAL B association
c
Degradation
TAL A degradation
TAL B degradation
d
Effect on transcription
TAL A effect
TAL B effect